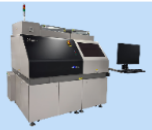
Auto Defect Classification

Purpose	Automatic Defect Classification capabilities available in STI optical inspection platforms enabling intelligent defect classification, reducing dependency on manual review and improving yield recovery
Technology	1. **Rule Based Auto Classification** – Defect classification is based on pre-define rule comparing various defect features and advanced statistical analysis. 2. **Zone Based Auto Classification** – Defect classification is performed by analyzing defect's location combined with advanced statistical analysis. 3. **AI Based Auto Review** – Apply Deep Learning/Machine Learning methodologies to eliminate manual defect review. 4. **PVI AI** – Apply Deep Learning/Machine Learning methodologies to recover yield from initial rejects.

STI Products	Rule Based Auto Classification	Zone Based Auto Classification	AI Based Auto Review	PVI AI
 **iFocus – Wafer 2D & 3D Scan**	✓	✓	✓	
 **Hexa – Tray 2D & 3D Scan**	✓	✓		✓
 **tSort - WLP Scan & Sort**	✓	✓		
 **tScan – 2D & 3D High Speed Scan-Pack**	✓	✓		✓